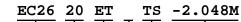
EC2620ETTS-2.048M





Series -RoHS Compliant (Pb-free) 3.3V 4 Pad 5mm x 7mm Ceramic SMD LVCMOS Oscillator

Solderability

Vibration

Temperature Cycling

Frequency Tolerance/Stability ±20ppm Maximum

- Nominal Frequency 2.048MHz

Pin 1 Connection Tri-State (High Impedance)

Duty Cycle 50 ±10(%)

Operatin -40°C to

ng	rem	peratu	re ka	nge –	_	
+8	35°C					

ELECTRICAL SPECIFICA	TIONS		
Nominal Frequency	2.048MHz		
Frequency Tolerance/Stability	±20ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Ouput Load Change, First Year Aging at 25°C, Shock, and Vibration)		
Operating Temperature Range	-40°C to +85°C		
Supply Voltage	3.3Vdc ±10%		
Input Current	10mA Maximum		
Output Voltage Logic High (Voh)	90% of Vdd Minimum (IOH=-8mA)		
Output Voltage Logic Low (Vol)	10% of Vdd Maximum (IOL=+8mA)		
Rise/Fall Time	5nSec Maximum (w/15pF Load), 7nSec Maximum (w/30pF Load) (Measured at 20% to 80% of waveform)		
Duty Cycle	50 ±10(%) (Measured at 50% of waveform)		
Load Drive Capability	30pF Maximum		
Output Logic Type	CMOS		
Pin 1 Connection	Tri-State (High Impedance)		
Tri-State Input Voltage (Vih and Vil)	+0.7Vdd Minimum or No Connect to Enable Output, +0.3Vdd Maximum to Disable Output (High Impedance)		
Standby Current	10µA Maximum (Disabled Output: High Impedance)		
RMS Phase Jitter	1pSec Maximum (12kHz to 20MHz offset frequency)		
Start Up Time	10mSec Maximum		
Storage Temperature Range	-55°C to +125°C		
ENVIRONMENTAL & MEC	HANICAL SPECIFICATIONS		
ESD Susceptibility	MIL-STD-883, Method 3015, Class 1, HBM: 1500V		
Fine Leak Test	MIL-STD-883, Method 1014, Condition A		
Flammability	UL94-V0		
Gross Leak Test	MIL-STD-883, Method 1014, Condition C		
Mechanical Shock	MIL-STD-883, Method 2002, Condition B		
Moisture Resistance	MIL-STD-883, Method 1004		
Moisture Sensitivity	J-STD-020, MSL 1		
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K		
Resistance to Solvents	MIL-STD-202, Method 215		

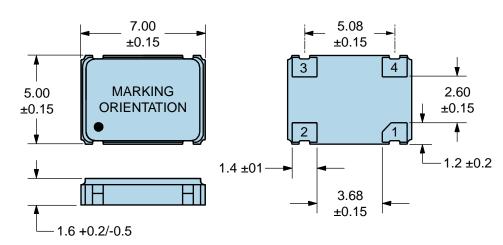
MIL-STD-883, Method 2003

MIL-STD-883, Method 1010, Condition B

MIL-STD-883, Method 2007, Condition A

EC2620ETTS-2.048M

MECHANICAL DIMENSIONS (all dimensions in millimeters)



PIN	CONNECTION			
1	Tri-State			
2	Ground/Case Ground			
3	Output			
4	Supply Voltage			
LINE	MARKING			
1	ECLIPTEK			
2	2.048M			
3	XXYZZ			

ECLIPTEK[®]

ECLIPTEK	
2.048M	
XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year	

Suggested Solder Pad Layout

All Dimensions in Millimeters



All Tolerances are ±0.1

EC2620ETTS-2.048M



OUTPUT WAVEFORM & TIMING DIAGRAM



Test Circuit for CMOS Output



Note 1: An external 0.1μ F low frequency tantalum bypass capacitor in parallel with a 0.01μ F high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

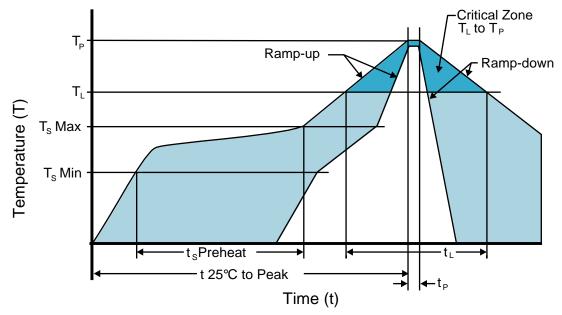
Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.



Recommended Solder Reflow Methods

EC2620ETTS-2.048M



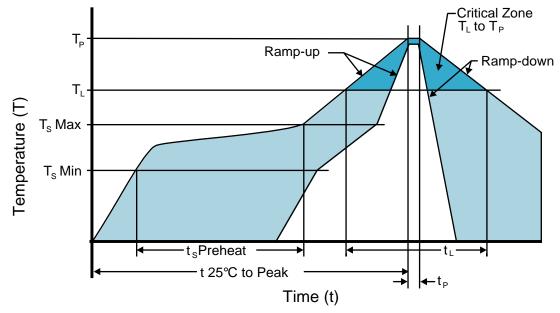
High Temperature Infrared/Convection

T _s MAX to T _L (Ramp-up Rate)	3°C/second Maximum	
Preheat		
- Temperature Minimum (T _s MIN)	150°C	
- Temperature Typical (T _s TYP)	175°C	
 Temperature Maximum (T_s MAX) 	200°C	
- Time (t _s MIN)	60 - 180 Seconds	
Ramp-up Rate (T⊾ to T _P)	3°C/second Maximum	
Time Maintained Above:		
- Temperature (T⊾)	217°C	
- Time (t∟)	60 - 150 Seconds	
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum	
Target Peak Temperature (T _P Target)	250°C +0/-5°C	
Time within 5°C of actual peak (t _P)	20 - 40 seconds	
Ramp-down Rate	6°C/second Maximum	
Time 25°C to Peak Temperature (t)	8 minutes Maximum	
Moisture Sensitivity Level	Level 1	
Additional Notes	Temperatures shown are applied to body of device.	



Recommended Solder Reflow Methods

EC2620ETTS-2.048M



Low Temperature Infrared/Convection 240°C

T_s MAX to T_L (Ramp-up Rate)	5°C/second Maximum	
Preheat		
- Temperature Minimum (T _s MIN)	N/A	
- Temperature Typical (T _s TYP)	150°C	
- Temperature Maximum (T _s MAX)	N/A	
- Time (t _s MIN)	60 - 120 Seconds	
Ramp-up Rate (T⊾ to T _P)	5°C/second Maximum	
Time Maintained Above:		
- Temperature (T∟)	150°C	
- Time (t∟)	200 Seconds Maximum	
Peak Temperature (T _P)	240°C Maximum	
Target Peak Temperature (T _P Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times	
Time within 5°C of actual peak (t _p)	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time	
Ramp-down Rate	5°C/second Maximum	
Time 25°C to Peak Temperature (t)	N/A	
Moisture Sensitivity Level	Level 1	
Additional Notes	Temperatures shown are applied to body of device.	

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)